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	FILING DATE November 2, 2000	GROUP 2858	
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FIGURE NO. IF APPROPRIATE
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<i>JP</i>	AB	4,473,796	9/25/1984	Nankivil			
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No
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